

Sheet 1 of 1

Subst. Form PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION <i>(Use several sheets if necessary)</i>	<table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <td style="width: 50%;">Docket Number (Optional) SAM-151</td> <td style="width: 50%;">Application Number</td> </tr> <tr> <td colspan="2">Applicant Won-Suk Yang t al.</td> </tr> <tr> <td>Filing Date Her with</td> <td>Group Art Unit 2811</td> </tr> </table>	Docket Number (Optional) SAM-151	Application Number	Applicant Won-Suk Yang t al.		Filing Date Her with	Group Art Unit 2811
Docket Number (Optional) SAM-151	Application Number						
Applicant Won-Suk Yang t al.							
Filing Date Her with	Group Art Unit 2811						

1c922 U.S. PTO
 09/699589
 10/30/00

U. S. Patent Documents							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>[Signature]</i>	AA	4,966,870	10/30/90	Barber et al.	437	228	8/8/89
<i>[Signature]</i>	AB	5,466,636	11/14/95	Cronin et al.	437	187	9/17/92
<i>[Signature]</i>	AC	5,612,254	3/18/97	Mu et al.	437	195	6/29/92
<i>[Signature]</i>	AD	5,808,335	9/15/98	Sung	257	306	7/14/97
<i>[Signature]</i>	AE	5,891,799	4/6/99	Tsui	438	624	8/18/97
<i>[Signature]</i>	AF	5,895,239	4/20/99	Jeng et al.	438	239	9/14/98
<i>[Signature]</i>	AG	5,918,120	6/29/99	Huang	438	239	7/24/98
<i>[Signature]</i>	AH	6,083,824	7/4/00	Tsai et al.	438	629	7/13/98
<i>[Signature]</i>	AI	6,022,776	2/8/00	Lien et al.	438	253	4/7/99
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							
	AQ							

OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
<i>[Signature]</i>	<table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <td style="width: 10%; text-align: center;">AR</td> <td>"Impact of passivation film deposition and post-annealing on the reliability of flash memories," Shuto et al., 1997 IEEE International Reliability Physics Symposium Proceedings (35th Annual), pgs. 17-24.</td> </tr> <tr> <td style="text-align: center;">AS</td> <td></td> </tr> <tr> <td style="text-align: center;">AT</td> <td></td> </tr> </table>	AR	"Impact of passivation film deposition and post-annealing on the reliability of flash memories," Shuto et al., 1997 IEEE International Reliability Physics Symposium Proceedings (35 th Annual), pgs. 17-24.	AS		AT	
AR	"Impact of passivation film deposition and post-annealing on the reliability of flash memories," Shuto et al., 1997 IEEE International Reliability Physics Symposium Proceedings (35 th Annual), pgs. 17-24.						
AS							
AT							
EXAMINER <i>[Signature]</i>	DATE CONSIDERED 6/26/03						
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy with next communication to applicant.							